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APPLICANT Johs et al.

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
I-A.	AA	5373359	12/1994	Woo Hm et al	356	328	
A	AB	5666201	9/1997	Johs et al	356	369	
	AC	5521706	5/1996	Green et al	356	369	
	AD	5504582	4/1996	Johs et al	356	369	
	AE	5757494	5/1998	Green et al	356	369	
	AF	5756145	9/1999	Green et al	356	364	
	AG	5706212	1/1998	Thompson et al	364	525	
	AH	5963327	10/1999	He et al	356	369	
	AI	5872630	2/1999	Johs et al	356	369	
	AJ	4053232	10/1997	Dill et al	356	118	
I-A.	AK	5946098	8/1999	Johs et al	356	364	

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
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Form PTO-146 Rev. 7-3-84	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DOCKET NO.	SERIAL NO.
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EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
I.A.	5 963325	10/1999	Jahr et al	356	364	
A	6 084674	7/2000	Jahr et al	356	364	
AC	6 084675	7/2000	Herzinger et al	356	369	
AD	6 100981	8/2000	Jahr et al	356	364	
AE	6 118537	9/2000	Jahr et al	358	369	
AF	6 141102	10/2000	Jahr et al	356	364	
AG	6 268917	7/2000	Jahr	356	369	
AH	4 5576292	12/1985	Mathysse et al	350	394	
AI	5 475525	12/1995	Tournais et al	359	240	
AJ	4 826321	5/1989	Coates et al	356	351	
I.A.	R 34783	11/1994	Coates	250	372	

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I.A.	AA	4 373817	2/1983	CooTter	356	384	
A	AB	5 045704	9/1991	CooTter	356	448	
	AC	4 647207	3/1987	Bjork et al	356	369	
	AD	4 210401	7/1980	Batt	356	369	
	AE	4 332476	6/1982	STenbergs et al	356	369	
	AF	4 355903	10/1982	Scandescotz	356	382	
	AG	4 838695	6/1989	Mansoripur et al	356	369	
	AH	4 750822	6/1988	Rosenwais et al	356	445	
	AI	5 042957	8/1991	Gold et al	356	369	
*	AJ	2 700918	2/1955	Osterberg et al			
I.A.	AK	3 183763	5/1965	Hoyer			

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I.A.	4105338	8/1978	Turah	356	118	
AB	3992104	11/1976	Watanae	356	117	
AC	5329357	7/1994	Bernoux et al	356	369	
AD	55781350	12/1996	Chen et al	356	369	
AE	5608526	3/1997	Piwonka-Corle et al	356	369	
AF	5596411	11/1997	Fantos et al.			
AG	5877859	3/1999	Aspnes et al	356	364	
AH	5798823	8/1998	Aspnes et al	357	369	
AI	5333652	7/1994	Fingrow	356	369	
AJ	5608526	3/1997	Piwonka-Corle et al	356	369	
I.A.	5793480	8/1998	Lacey et al	356	73	

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
I. A.	AA	4636075	1/1987	Hollenberg	356	336	
A	AB	4893932	1/1990	Hollenberg	356	369	
A	AC	4668860	5/1987	Anthon	250	225	
T. A.	AD	5917594	6/1999	Norton	356	327	
	AE						
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Paper by Johs, titled "Regression Calibration Method for Rotating Element Ellipsometers", Thin Solid Films, 234 (1993).

Paper, by Gottesfeld et al., titled "Combined Ellipsometer and Reflectometer Measurements of Surface Processes on Nobel Metals Electrodes", Surface Sci., 56 (1976).

Paper by Smith, titled "An Automated Scanning Ellipsometer", Surface Science, Vol. 56, No. 1. (1976).

Papers, by Azzam and Azzam et al. are also identified as concerning alternative approaches to the goal of the present invention, and are titled:

"Multichannel Polarization State Detectors For Time-Resolved Ellipsometry", Thin Solid Film, 234 (1993); and

"Spectrophotopolarimeter Based On Multiple Reflections In A Coated Dielectric Slab", Thin Solid Films 313 (1998); and

"General Analysis And Optimization Of The Four-Detector Photopolarimeter", J. Opt. Soc. Am., A, Vol. 5, No. 5 (May 1988); and

"Accurate Calibration Of Four-Detector Photopolarimeter With Imperfect Polarization Optical Elements", J. Opt. Soc. Am., Vol. 6, No. 10, (Oct. 1989);

Review paper by Collins, titled "Automatic Rotating Element Ellipsometers: Calibration, Operation and Real-Time Applications", Rev. Sci. Instrum., 61(8) (1990), is identified for general information.



2/11/06